



Search Notes 	Application/Control No. 10653757	Applicant(s)/Patent Under Reexamination LUSTIG ET AL.
	Examiner Washburn, Douglas N	Art Unit 2863

Notes	Date	Examiner
Inventor name search - Update - see printout - (USPGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TD)	06/15/2006	DNW
EAST keyword/keyphrase - Update - see printout - (USPGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB)	08/14/2006	DNW
B01J019/00 - Update - see printout - (USPGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB)	06/15/2006	DNW
G01N021/52 - Update - see printout - (USPGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB)	07/25/2006	DNW
G01N033/00 - Update - see printout - (USPGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB)	07/25/2006	DNW
702/30, 31 - Update - see printout - (USPGPUB; USPAT; USOCR)	07/25/2006	DNW
Hoff, M AU 2857; 101 consult; suggested 101 rejection applicable to method claims	06/13/2006	DNW
G01N021/52 see printout - (USPGPUB; USPAT; USOCR; FRPS; EPO; JPO; DERWENT; IBM_TDB)	07/25/2006	DNW
422/119, 122, 130	08/14/2006	DNW
IEEE keyword/keyphrase - see printout - (USPGPUB; USPAT; USOCR; FRPS; EPO; JPO; DERWENT; IBM-TDB)	08/01/2006	DNW
Ludlow, J AU 1743; consult regarding claims 22, 27 and 32; suggested search 436/174, 179	07/24/2006	DNW
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<p>Searched</p> 	<p>Application/Control No.</p> <p>10653757</p>	<p>Applicant(s)/Patent Under Reexamination</p> <p>LUSTIG ET AL.</p>
	<p>Examiner</p> <p>Washburn, Douglas N</p>	<p>Art Unit</p> <p>2863</p>

Class	SubClass	Date	Examiner
702	31	07/25/2006	DNW
702	30	07/25/2006	DNW
436	46	07/25/2006	DNW
436	179	07/25/2006	DNW

Handwritten notes in the Examiner column: 'mu' with an arrow pointing up from the 436/179 row to the 702/30 row, and 'tw' with an arrow pointing down from the 702/30 row to the 436/46 row.

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